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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Eric J STRANG, et al.

FILING DATE

September 30, 2003

GROUP

2128

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	US 2002/0032495 A1	3/14/2002	Ozaki			
	AB						
	AC						
	AD						
	AE						
	AK						
	AF						
	AG						
	AH						

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AI	CN 1335558A	2/13/2002	China (with Partial English Translation))	X	
	AJ	EP 0 718 595 A2	6/26/1996	EUROPE		X
	AK	WO 02/07210 A2	1/24/2002	WIPO		X
	AL	JP 11-176906	7/2/1999	JAPAN (with English Abstract)		X
	AM	KR 1999-071784	4/2/1999	Korea (with corresponding to US. Patent Application No. 5,719,796 attached as a courtesy herewith)	X	

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AN	Agam SHAH, "TILERA TARGETS INTEL, AMD WITH 100-CORE PROCESSOR", PCWorld Solved, IDG News October 26, 2009, pages 1-3
	AO	Robert W. ATHERTON, et al., "DETAILED SIMULATION FOR SEMICONDUCTOR MANUFACTURING", Proceedings of the 1990 Winter Simulation Conference, ppgs 659-663
	AP	Angus J. MACDONALD, et al. "INTEGRATING CAM AND PROCESS SIMULATION TO ENHANCE ON-LINE ANALYSIS AND CONTROL OF IC FABRICATION", IEEE Transactions On Semiconductor Conductor Manufacturing, Vol., 3. No. 2, May 1990, pages 72-79
	AQ	Paul P. CASTRUCCI, et al. "EMERGING PARADIGMS IN SEMICONDUCTOR MANUFACTURING", 1990 International Semiconductor Manufacturing Science Symposium, pages 21-23
	AR	Yea-Huey Su, et al, "A CONCEPTUAL FRAMEWORK FOR MANUFACTURING SERVICE PROVISIONING BY VIRTUAL FABS", 1998 Semiconductor Manufacturing Technology Workshop, pages 75-85
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	AT	Office Action issued March 30, 2011 in Japanese Patent Application No. 10-2006-7006632, (with English-language Translation), pages 1-18
	AU	Office Action issued June 19, 2009 in The People's Republic of China Patent Application No. 200480028517.6, (with English-language Translation), pages 1-39
	AV	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.